

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	24	("4433982" "4599095" "5087275" "5151110" "5224972" "5501893" "5589396" "5720798" "5770275" "5939614").PN. OR ("6171378").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/02/01 14:02
L2	17	("4633578" "4696188" "4784721" "5251481" "5263380" "5313832" "5445991" "5565084" "5620929" "5801070" "5804720" "5830372" "5868947" "5968336" "6004450").PN. OR ("6139758").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/02/01 14:18
L3	29	((microfluidic adj channel) same (silicon si)) and heat\$3 and (thermopile thermocouple thermocoupler)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 14:30
L4	112	((microfluidic adj channel) same (silicon si)) and (etch\$3 with (silicon si)) and (inlet input) and (outlet output)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 14:33
S1	1	("6359276").PN.	USPAT	OR	ON	2006/02/01 13:16

S2	97	("5389218" "5389225" "5468605" "5659138" "5665250" "6225140" "6225140" "5922249" "5861902" "5387803" "5569626" "5919364" "5939732" "6210987" "6210987" "6478974" "4272986" "4786396" "5578528" "5242863" "5311775" "5736430" "5834333" "5852308" "5861545" "5892140" "6118164" "6743654" "6803637" "4308190" "6209992" "6209992" "6297377" "6384113" "6444833" "6147359" "6090724" "6309611" "6315870" "4963396" "5391232" "4277742" "5882496" "6004450" "4595485" "4845978" "5271821" "5599584" "5902556" "6133572").pn. ("6165336" "6151347" "4381818" "5352635" "5386142" "5386143" "5401672" "5455445" "5461001" "5632320" "5729970" "5947094" "3892835" "3852099" "4247304" "4258783" "4332242" "4353953" "4357222" "4417888" "4430389" "4446100" "4446579" "4478789" "4496349" "4508671" "4530378" "4612163" "4756895" "4804033" "4838915" "4927600" "4931354" "4981665" "4983423" "5000245" "5002905" "5004036" "5005631" "5010945" "5016703" "5017100" "5188164" "5197528" "5202105" "5207263" "5224533" "5240672" "5247986" "5267601").pn.	USPAT	OR	ON	2006/01/30 12:26
S3	6414	porous adj (silicon si)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 12:46
S4	584	electrochemical adj dissolution	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 12:46
S5	104077	current adj density	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 12:47

S6	21404	cavity same membrane	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 12:47
S7	1	(S3 same S4) and (S4 same S5) and (S3 same S6)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 12:47
S8	6	S3 and S4 and S5 and S6	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 12:52
S9	0	("2005/0072926").URPN.	USPAT	OR	ON	2006/01/30 12:49
S10	8	S3 and S4 and S6	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 12:50
S11	2	S10 not S8	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 12:52
S12	1	"5348618".pn.	USPAT	OR	ON	2006/01/30 12:52
S13	5	(S3 same S4) and (S4 same S5)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 12:53
S14	4	S13 not (S7 S8 S10)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 12:55
S15	4441	electropolish\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 12:55

S16	5113	(electrochemical electro-chemical (electro adj chemical)) with (dissolution dissolv\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 12:55
S17	26804	porous with (silicon si crystalline)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 13:05
S18	77	S16 same S17	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 13:05
S19	14	S15 and S18	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 12:56
S20	63	S18 not S19	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 12:59
S21	975	S17 with membrane	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 13:06
S22	18	S21 and S16	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 12:59
S23	7252	porous with (semiconduct\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 13:05

S24	12	S16 same S23	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 13:05
S25	244	S23 with membrane	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 13:06
S26	2	S25 and S16	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 13:31
S27	5	("20020094435" "20040038228" "5345213" "5464966" "5969231").PN.	US-PGPUB; USPAT	OR	ON	2006/01/30 13:34
S28	8564	(microfluid\$2 micro-fluid\$2)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 13:34
S29	4999105	detect\$3 sens\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 13:35
S30	283	S28 and S29 and (S17 S23)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 13:36
S31	1952252	thermocoupl\$3 thermopile thermal\$2 (temperature with (detect\$3 sens\$3))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 13:49
S32	227	S30 and S31	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 13:50
S33	1	US-20040195096-A1	US-PGPUB	OR	ON	2006/01/30 13:46
S34	0	("2004/0195096").URPN.	USPAT	OR	ON	2006/01/30 13:47

S35	520251	thermocoupl\$3 thermopile (temperature with (detect\$3 sens\$3))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 13:49
S36	105	S30 and S35	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 13:50
S37	2	wo-9850763-\$ did.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 14:39
S38	6423	porous adj (silicon si)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 10:15
S39	184	S38 with membrane	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 10:15
S40	1914152	channel	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 10:15
S41	15	S39 same S40	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 10:16
S42	81	S39 and S40	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 10:15

S43	66	S42 not S41	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 10:17
S44	5000715	detect\$3 sens\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 10:18
S45	127	(S44 and (S38 same channel)) not S42	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 10:32
S46	221	438/54.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 10:32
S47	8	S46 and (porous with (silicon si crystalline semiconduct\$3))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 10:35
S48	173	438/411.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 10:35
S49	18	S48 and (porous with (silicon si crystalline semiconduct\$3))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 10:35
S50	8575	(microfluid\$2 micro-fluid\$2)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 11:56

S51	5000715	detect\$3 sens\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 11:56
S52	2509	S50 with S51	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 11:56
S53	97	thermal with S52	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 11:57
S54	27232	passivation adj layer	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 11:57
S55	8	S53 and S54	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 12:11
S56	56	S53 and ((silicon adj (oxide dioxide nitride)) (polyimide))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 12:13
S57	205	S50 and S51 and channel and heater and (thermocouple thermocoupler thermopile)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 12:26
S58	22	S57 and S54	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 12:26

S59	5000715	detect\$3 sens\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 13:17
S60	1481	(thermal adj (flow fluidic)) and S59	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 13:20
S61	6423	porous adj (silicon si)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 13:20
S62	6	S60 and S61	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 13:27
S63	36	S60 and (channel microchannel) and (silicon si) and (cavity) and (membrane hotplate)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 13:29

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5	INZZ	detector OR sensor	unrestricted	232990	show titles
6	INZZ	4 AND 5	unrestricted	12	show titles
7	INZZ	(1 AND membrane) NOT 3	unrestricted	102	show titles
8	INZZ	7 AND channel AND 5	unrestricted	0	-
9	INZZ	7 AND channel	unrestricted	2	show titles
10	INZZ	(7 AND 5) NOT 9	unrestricted	41	show titles
11	INZZ	limit set 4 YEAR < 2003	unrestricted	21	show titles
12	INZZ	limit set 7 YEAR < 2003	unrestricted	68	show titles
13	INZZ	limit set 10 YEAR < 2003	unrestricted	32	show titles
14	INZZ	thermal WITH (flow OR fluid OR fluidic)	unrestricted	18742	show titles
15	INZZ	5 AND 14	unrestricted	555	show titles
16	INZZ	15 AND membrane	unrestricted	34	show titles
17	INZZ	15 AND 1	unrestricted	15	show titles
18	INZZ	15 AND silicon AND channel	unrestricted	14	show titles

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8	INZZ	Cavani-F.AU.	unrestricted	8	show titles
9	INZZ	porous ADJ (silicon OR si)	unrestricted	5909	show titles
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